

Search Notes**Application/Control No.**

10/534,134

Examiner

Sang Y. Paik

Applicant(s)/Patent under Reexamination

JEONG ET AL.

Art Unit

3742

SEARCHED

Class	Subclass	Date	Examiner
392	386		
	387		
	388		
	389		
118	726		
420	192		
	193		
	113		
428	401		
	216	4/27/06	SP

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
ENTRAT REFERRED	4/27/06	SP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner